Reliability Report – LM193

Dual Differential Comparator - Low power, low offset voltage

MIL-PRF-38534 CLASS K QUALIFICATION DATAPACK

Performed by Tandex Test Labs

TANDEX

15849 Business Center Drive, Irwindale, CA 91706, U.S.A.
Phone (626) 962-7166, Fax (626) 960-6896
www.tandexlabs.com

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- Scanning Electron Microscopy (SEM) analysis.

Certificate of Conformance

TANDEX TEST LABS, INC.

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e-mail: via web site

Certificate of Conformance

CUSTOMER:	**SILICON SUPPLIES LIMITED** **47 WHERRY ROAD** **NORWICH, NR1, 1WS** **UNITED KINGDOM VAT** **GB#114 3513 56**	**Revised Date: November 27, 2018 DATE: AUGUST 29, 2018	
TEST REPORT:	***DDS-101-17-A***	QUANTITY RECEIVED:	***30 DIE***
P.O. NUMBER:	***SS139***	QUANTITY REQUIRED:	*10/5/8*
DESCRIPTION:	***VOLTAGE COMPARATOR MICROCIRCUIT***	QUANTITY PROCESSED:	*17*
PART NUMBER(S):	*****LM193***	QUANTITY PASSED:	*17*
P/N: AS RECEIVED / MFG. PART NUMBER:	*****LM193***	QUANTITY FAILED:	*0*
LOT / DATE CODE:	***1810 LOT# 430549 WF30***		
MANUFACTURE: CAGE CODE:	***SILICON SUPPLIES***	***QUANTITY SHIPPING:***	***17****
		INCLUDES: 10 PROCESS ACCEPT 5 BOND PULL DEVICES 2 SPARES	
TANDEX CAGE CODE:	***1FE65***	**8 DIE TRANSFERRED TO DDS-101-17-W FOR SEM.*	

METHOD OF TESTING: MIL-PRF-38534 CL. K, MIL-STD-883

I hereby certify that the subject components have been processed and inspected in accordance with instructions with specifications referenced in your purchase order. Physical records and/or data pertinent to applicable military, proprietary, and/or commercial specifications are on file and available upon request for inspection at this facility.

Linda S. Sepulveda
QUALITY ASSURANCE

QA TANDEX 5

QMF 30

Process Flow Chart + Mechanical Test Results

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QMF22B

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PROCESS FLOW CHART

FLOW NUMBER: DDS-101-17-A REV. 0

CUSTOMER: DIE DEVICES
P.O. NUMBER: SS139
PART NUMBER: LM193
P/N AS RECEIVED: LM193
PART TYPE: VOLTAGE COMPARATOR MICROCIRCUIT
DRAWING: MIL-PRF-38534 CL K, MIL-STD-883
DUE DATE: 7/12/18
JOB NUMBER: DDS-101-17-A
LDC AS RECEIVED: 1810 LOT# 430549 WF30
QUANTITY RECEIVED : 30 (DIE)
QUOTE NUMBER: DDS14267-1 MFG: SILICON SUPPLIES
QUANTITY REQUIRED : 10/5/8

CAUTION: ESD REFER TO TTL DRAWING #P1025

SEQ	PROC	REF #	DESCRIPTION	QTY	REJ	ACCEPT	DATE	INSP.
01	FLO	P-1015 P-1223	FLOW PREPARED BY: LSS . ON: 3/29/18 . CONTRACTUAL AGREEMENT REVIEW Y / N / NOT SPECIFIED ☐ ☐ ☒ Q-CLAUSES ☐ ☒ ☐ DPAS ☐ ☒ ☐ DFAR ☐ ☒ ☐ ITAR ☐ ☐ OTHER _____ SPECIFIED					QA TANDEX 5
02	QCI		TANDEX QUALITY CONTROL INSPECTION. FLOW APPROVED BY: JMI . ON: 3/29/18 .					QA TANDEX 7
03	RCV	P-1070	VERIFY PART NUMBER. ENTER INTO INCOMING LOG. X CUSTOMER COUNT	30			3/29/18	QA TANDEX 5
04	VIS	P-1041	PERFORM 100% DIE VISUAL PER MIL-STD-883 METHOD 2010 AND MIL-PRF-38534 PARA C.3.3.2. ESD MAT DUE DATE: 6/20/18. EQUIPMENT USED: Olympus . ASSET #: 20091 .	30	Ø	30	5/31/18	TTL 1
05	ASSY	P-1029	PACKAGE SUFFICIENT DEVICES FOR CLASS K ELEMENT EVALUATION / ELECTRICAL AND BOND PULL PER MIL-PRF-38534 REFERENCE DIE GEOMETRY FOR ORIENTATION AND PIN – OUTS. DIE ATTACH: SCREENING EUTETIC Lot#: 149555 Exp. Date: NA ESD MAT DUE DATE: 6/27/18. * **Package Type: 8 PIN DIP**	10+2	Ø	10+2	6/05/18	TTL 27
			BOND PULL	5	Ø	5	6/05/18	TTL 27
			SEM TRANSFER TO DDS-101-17-W MIL-STD-883 METHOD 2018	8	Ø	8	5/31/18	TTL 1
		P-4010	WIRE BOND: Utilize 1 Mil Au Wire (.001) 1 Mil Au bonder MECH-EL Asset #: 20060 Gold Wire: Lot#: 900301196O Exp. Date: 3/16/2020	17	Ø	17	6/5/18	TTL 30

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PROCESS FLOW CHART

FLOW NUMBER: DDS-101-17-A REV. 0

CUSTOMER: DIE DEVICES
P.O. NUMBER: SS139
PART NUMBER: LM193
P/N AS RECEIVED: LM193
PART TYPE: VOLTAGE COMPARATOR MICROCIRCUIT
DRAWING: MIL-PRF-38534 CL K, MIL-STD-883
DUE DATE: 7/12/18
JOB NUMBER: DDS-101-17-A
LDC AS RECEIVED: 1810 LOT# 430549 WF30
QUANTITY RECEIVED : 30 (DIE)
QUOTE NUMBER: DDS14267-1 MFG: SILICON SUPPLIES
QUANTITY REQUIRED : 10/5/8

CAUTION: ESD REFER TO TTL DRAWING #P1025

SEQ	PROC	REF #	DESCRIPTION	QTY	REJ	ACCEPT	DATE	INSP.
06	VIS		PERFORM 100% INTERNAL VISUAL PER MIL-STD-883 METHOD 2010 & MIL-PRF-38534 C.3.3.3, C.3.3.4.2. ESD MAT DUE DATE: 6/27/18 EQUIPMENT USED: Bausch Lomb. ASSET #: 30772	17	Ø	17	6/05/18	TTL 27
07	SEAL		SEAL DEVICES VACUUM BAKE: ESD MAT DUE DATE: 6/27/18 Pre Seal Bake Time: Temp: 124 Time: 11:00 AM Actual time in: 11:00 AM 6/05/18 Actual time out: 11:45 Actual temp: 124 FURNACE 1822 LDC STAMP TTL 27	10+2	Ø	10+2	6/06/18	TTL 27
08	ELEC		PERFORM 100% ELECTRICAL VERIFICATION TEST PER MFG DATA SHEET AND MIL-PRF-38534 @ AMBIENT OPERATING TEMPERATURE GO / NO GO ESD MAT DUE DATE: 6/27/18 EQUIPMENT USED: LTS 2020 ASSET#: 20013 +25°C TEST FIXTURE: #17 SOFTWARE ID: $LM193 REV N/A	10+2	Ø	10+2	6/7/18	TTL 13
09	TEMP		PERFORM TEMPERATURE CYCLING PER MIL-STD-883 METHOD 1010 CONDITION C & MIL-PRF-38534 C.3.3.3. TEN (10) CYCLES TA = -65°C +0/-10 to +150°C +15/-0 10 MINUTES AT EXTREMES EQUIPMENT USED: DELTA DESIGN ASSET #: 30626 EQUIPMENT USED: OMEGA HH309A ASSET #: 31567	DATE IN TIME IN 10+2 DATE OUT TIME OUT 10+2	Ø Ø	10+2 10+2	6/8/18 5:49A.M 6/8/18 10:31A.M	TTL 48 TTL 48
10	ACCE		PERFORM CONSTANT ACCELERATION PER MIL-PRF-38534 MIL-STD-883 METHOD 2001. ESD MAT DUE DATE: 6/27/18 Y1 DIRECTION ONLY @ 3000 G's (min) EQUIPMENT USED: TRIOTECH ASSET #: 30260	10+2	0	10+2	6/12/18	TTL 52
11	SER		SERIALIZE ESD MAT DUE DATE: 6/27/18 S/N: ~~01-10~~ 01-12 6/12/18	10+2	0	10+2	6/14/18	TTL 19

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PROCESS FLOW CHART

FLOW NUMBER: DDS-101-17-A REV. 0

CUSTOMER: DIE DEVICES
P.O. NUMBER: SS139
PART NUMBER: LM193
P/N AS RECEIVED: LM193
PART TYPE: VOLTAGE COMPARATOR MICROCIRCUIT
DRAWING: MIL-PRF-38534 CL K, MIL-STD-883
DUE DATE: 7/12/18
JOB NUMBER: DDS-101-17-A
LDC AS RECEIVED: 1810 LOT# 430549 WF30
QUANTITY RECEIVED : 30 (DIE)
QUOTE NUMBER: DDS14267-1 MFG: SILICON SUPPLIES
QUANTITY REQUIRED : 10/5/8

CAUTION: ESD REFER TO TTL DRAWING #P1025

SEQ	PROC	REF #	DESCRIPTION	QTY	REJ	ACCEP	DATE	INSP.
12	ELEC		PERFORM 100% ELECTRICAL VERIFICATION PER MFG DATA SHEET3 AND MIL-PRF-38534 C.3.3.4.3 @ AMBIENT , HIGH AND LOW OPERATING TEMPERATURES. READ AND RECORD. ESD MAT DUE DATE: 6/27/18 STATIC AND FUNCTIONAL TESTS +25°C 10+2 0 10+2 6/20/18 TTL 52 - 55°C 10+2 0 10+2 6/20/18 TTL 52 +125°C 10+2 0 10+2 6/20/18 TTL 52 EQUIPMENT USED: LTS 2020 ASSET#: 20013 TEST FIXTURE: 17 SOFTWARE ID: $LM193 REV N/A TEMPERATURE SOAK 10 SEC.					
13	BI		PERFORM BURN IN PER BURN IN CIRCUIT PER FIGURE 1 OF DWG# 1026-16668, AND MIL-STD 883 METHOD 1015. ESD MAT DUE DATE: 7/27/18. TA = 125°C (min) T = 240 HRS (min) DATE IN: 6/21/18 TIME IN: 11:00AM BURN-IN BOARD # / DESC: 31267 BURN-IN OVEN #: 21 DATE OUT: 7/2/18 TIME OUT: 5:30PM	12	0	12	6/21/18 11:00AM 7/2/18 5:30PM	TTL 13 TTL 13
14	ELEC		PERFORM POST BURN IN ELECTRICAL VERIFICATION PER MFG DATA SHEET AND MIL-PRF-38534 C.3.3.4.3 @ AMBIENT, HIGH AND LOW OPERATING TEMPERATURES. READ AND RECORD. ESD MAT DUE DATE: 7/27/18. STATIC AND FUNCTIONAL TESTS TEST +25°C WITHIN 96 HOURS +25°C 12 0 12 7/03/18 TTL 27 - 55°C 12 0 12 7/03/18 TTL 27 +125°C 12 0 12 7/03/18 TTL 27 EQUIPMENT USED: LTS 2020 ASSET#: 20013 TEST FIXTURE: 17 SOFTWARE ID: $LM193 REV N/A TEMPERATURE SOAK 10 SEC.					
15	ER		PER PO REQUIREMENTS: REVIEW AT POST 240 HR. BURN-IN EMAIL: ben.white@diedevices.com POST 240 HR BURN-IN ELECTRICAL TEST DATA. HOLD FOR APPROVAL TO PROCEED DATE SENT: 07/03/18					QA TANDEX 7

TANDEX TEST LABS

BURN - IN MONITOR SHEET

JOB NUMBER DDS-101-17-A

PART NUMBER LM193

DATE CODE 1810 LOT # 430549 WF30

BURN-IN TIME 240 hrs

θJC= N/A

TEMPERATURE TA=+125°C

TEMP. METER # 31368

VOLTAGE VCC= +30VDC

VOLT METER# 31223

POWER SUPPLY# 31652

BOARD# 31267

OVEN# 21

DATE	TIME	VOLTAGE	CURRENT	TEMP.	INITIAL	COMMENTS
6/21/18	11:00AM	VCC=+30VDC	ICC=.27A	127.1°C	CM	
6/22/18	9:20AM	VCC=+30VDC	ICC=.27A	127.3°C	CM	
6/25/18	6:00AM	VCC=+30VDC	ICC=.27A	126.5°C	CM	
6/26/18	7:30AM	VCC=+30VDC	ICC=.27A	126.9°C	CM	
6/27/18	7:15AM	VCC=+30VDC	ICC=.27A	126.4°C	CM	
6/28/18	8:55AM	VCC=+30VDC	ICC=.27A	126.6°C	CM	
6/29/18	6:00AM	VCC=+30VDC	ICC=.27A	127.7°C	CM	
7/2/18	5:30AM	VCC=+30VDC	ICC=.27A	127.7°C	CM	

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PROCESS FLOW CHART

FLOW NUMBER: DDS-101-17-A REV. 0

CUSTOMER: DIE DEVICES
P.O. NUMBER: SS139
PART NUMBER: LM193
P/N AS RECEIVED: LM193
PART TYPE: VOLTAGE COMPARATOR MICROCIRCUIT
DRAWING: MIL-PRF-38534 CL K, MIL-STD-883
DUE DATE: 7/12/18
JOB NUMBER: DDS-101-17-A
LDC AS RECEIVED: 1810 LOT# 430549 WF30
QUANTITY RECEIVED : 30 (DIE)
QUOTE NUMBER: DDS14267-1 MFG: SILICON SUPPLIES
QUANTITY REQUIRED : 10/5/8

CAUTION: ESD REFER TO TTL DRAWING #P1025

SEQ	PROC	REF #	DESCRIPTION	QTY	REJ	ACCEPT	DATE	INSP.
16	SSL		PERFORM STEADY STATE LIFE TEST PER MIL-PRF-38534 AND MIL-STD 883 METHOD 1005. TA = 125°C (min) T = 1000 HRS (min) DATE IN: / TIME IN: DATE OUT: / TIME OUT: BURN-IN BOARD # / DESC: 31267 BURN-IN OVEN #: 21 ESD MAT DUE DATE: 8/27/18.	12 12	0 0	12 12	7/4/18 7:00AM 8/20/18 5:00PM	TTL 13 TTL 13
17	ELEC		PERFORM POST STEADY STATE LIFE ELECTRICAL VERIFICATION PER MFG DATA SHEET AND MIL-PRF-38534 C.3.3.4.3. @ AMBIENT, HIGH AND LOW OPERATING TEMPERATURE. READ AND RECORD. STATIC AND FUNCTIONAL TESTS TEST +25°C WITHIN 96 HOURS +25°C - 55°C +125°C EQUIPMENT USED: LTS2020 . ASSET#: 20013 TEST FIXTURE: 17 SOFTWARE ID: $LM193 REV N/A ESD MAT DUE DATE: 8/27/18	12 12 12	0 0 0	12 12 12	8/20/18 8/20/18 8/20/18	TTL 53 TTL 53 TTL 53
18	DBP		PERFORM WIRE BOND PULL PER MIL-STD-883 METHOD 2011, & MIL-PRF-38534 C.3.3.3, C3.3.5. TEN (10) WIRES, ***DO NOT USE ELECTRICAL TEST SAMPLES*** EQUIPMENT USED: DAGE . ASSET #: 30785	5	0	5	8/6/18	#4 QA TANDEX
19	SEM		PULLED 8 DEVICES AT SEQ. 05 AND TRANSFERRED TO: DDS-101-17-W	8	0	8	5/31/18	QA TANDEX

TANDEX TEST LABS
BURN - IN MONITOR SHEET

JOB NUMBER DD5-161-17-A

PART NUMBER 2M193

DATE CODE 1810 LOT # 430549 WF30

BURN-IN TIME 1000hrs Min

θJC= N/A

TEMPERATURE TA=+125°C Min

TEMP. METER # 31368

VOLTAGE VCC=+30VDC

VOLT METER# 31223

POWER SUPPLY# 31652

BOARD# 31267

OVEN# 21

DATE	TIME	VOLTAGE	CURRENT	TEMP.	INITIAL	COMMENTS
7/9/18	7:00AM	VCC=+30VDC	ICC=.27A	127.8°C	CM	
7/10/18	1:10 PM	VCC=+30VDC	ICC=.27A	128.5°C	CM	
7/11/18	10:00AM	VCC=+30VDC	ICC=.27A	127.7°C	CM	
7/12/18	7:20AM	VCC=+30VDC	ICC=.27A	127.5°C	CM	
7/13/18	6:05AM	VCC=+30VDC	ICC=.27A	127.9°C	CM	
7/16/18	6:00AM	VCC=+30VDC	ICC=.27A	127.6°C	CM	
7/17/18	6:15AM	VCC=+30VDC	ICC=.27A	128.0°C	CM	
7/18/18	6:00AM	VCC=+30VDC	ICC=.27A	128.2°C	CM	
7/19/18	NO	DATA	TAKEN			
7/20/18	NO	DATA	TAKEN			

TANDEX TEST LABS

BURN - IN MONITOR SHEET

JOB NUMBER DD5-101-17-A

PART NUMBER 2M193

DATE CODE 1810 LOT # 430549 WF30

BURN-IN TIME 1000hrs Min

θJC= N/A

TEMPERATURE TA=+125°C Min

TEMP. METER # 31368

VOLTAGE VCC=+30VDC

VOLT METER# 31223

POWER SUPPLY# 31652

BOARD# 31267

OVEN# 21

DATE	TIME	VOLTAGE	CURRENT	TEMP.	INITIAL	COMMENTS
7/23/18	NO	DATA	TAKEN			
7/24/18	NO	DATA	TAKEN			
7/25/18	7:25AM	VCC=+30VDC	ICC=.27A	126.1°C	CM	
7/26/18	6:00AM	VCC=+30VDC	ICC=.27A	126.4°C	CM	
7/27/18	7:25AM	VCC=+30VDC	ICC=.27A	126.6°C	CM	
7/30/18	10:50AM	VCC=+30VDC	ICC=.27A	127.8°C	CM	
7/31/18	6:55AM	VCC=+30VDC	ICC=.27A	127.6°C	CM	
8/1/18	6:20AM	VCC=+30VDC	ICC=.27A	128.8°C	CM	
8/2/18	11:10AM	VCC=+30VDC	ICC=.27A	127.3°C	CM	
8/3/18	6:45AM	VCC=+30VDC	ICC=.27A	127.3°C	CM	

TANDEX TEST LABS

BURN - IN MONITOR SHEET

JOB NUMBER DD5-101-17-A

PART NUMBER 2M193

DATE CODE 1810 LOT # 430549 WF30

BURN-IN TIME 1000hrs Min

θJC= N/A

TEMPERATURE TA=+125°C Min

TEMP. METER # 31368

VOLTAGE VCC=+30VDC

VOLT METER# 31223

POWER SUPPLY# 31652

BOARD# 31267

OVEN# 21

DATE	TIME	VOLTAGE	CURRENT	TEMP.	INITIAL	COMMENTS
8/6/18	6:00AM	VCC=+30VDC	ICC=.27A	126.1°C	CM	
8/7/18	8:35AM	VCC=+30VDC	ICC=.27A	125.5°C	CM	
8/8/18	6:00AM	VCC=+30VDC	ICC=.27A	126.2°C	CM	
8/9/18	6:30AM	VCC=+30VDC	ICC=.27A	126.0°C	CM	
8/10/18	6:45AM	VCC=+30VDC	ICC=.27A	125.7°C	CM	
8/13/18	5:40AM	VCC=+30VDC	ICC=.27A	125.6°C	CM	
8/14/18	NO	DATA	TAKEN			
8/15/18	NO	DATA	TAKEN			
8/16/18	6:05AM	VCC=+30VDC	ICC=.27A	126.1°C	CM	

TANDEX TEST LABS

BURN - IN MONITOR SHEET

JOB NUMBER DD5-101-17-A

PART NUMBER 2M193

DATE CODE 1810 LOT # 430549 WF30

BURN-IN TIME 1000hrs Min

θJC= N/A

TEMPERATURE TA=+125°C Min

TEMP. METER # 31368

VOLTAGE VCC=+30mC

VOLT METER# 31223

POWER SUPPLY# 31652

BOARD# 31267

OVEN# 21

DATE	TIME	VOLTAGE	CURRENT	TEMP.	INITIAL	COMMENTS
8/17/18	9:35 A	VCC:+30mC	ICC:.27A	126.1°C	CM	
8/20/18	5:45 AM	VCC=+30mC	ICC:.27A	126.1°C	CM	

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PROCESS FLOW CHART

FLOW NUMBER: DDS-101-17-A REV. 0

CUSTOMER: DIE DEVICES
P.O. NUMBER: SS139
PART NUMBER: LM193
P/N AS RECEIVED: LM193
PART TYPE: VOLTAGE COMPARATOR MICROCIRCUIT
DRAWING: MIL-PRF-38534 CL K, MIL-STD-883
DUE DATE: 7/12/18
JOB NUMBER: DDS-101-17-A
LDC AS RECEIVED: 1810 LOT# 430549 WF30
QUANTITY RECEIVED : 30 (DIE)
QUOTE NUMBER: DDS14267-1 MFG: SILICON SUPPLIES
QUANTITY REQUIRED : 10/5/8

CAUTION: ESD REFER TO TTL DRAWING #P1025

SEQ	PROC	REF #	DESCRIPTION	QTY	REJ	ACCEPT	DATE	INSP.
20	QCI	P-1073	TANDEX QUALITY CONTROL INSPECTION. QCI TO VERIFY CAR IN SEQ. 01 IS COMPLIANT	10/5	0	10/5	8/29/18	QC TANDEX 1
21	PKG		USE ORIGINAL OR TANDEX PACKAGING.	10/5	0	10/5	8/29/18	QC TANDEX 1
22	QAR	P-1213	TANDEX QUALITY ASSURANCE REVIEW. SHIP VIA: SHIP / BILL TO: DIE DEVICES 47 WHERRY ROAD NORWICH, NR1, 1WS UNITED KINGDOM VAT GB#114 3513 56	~~10/5~~ 10 10+2/5			8/29/18	QC TANDEX 1 QA TANDEX 5

* Includes:
10 process Accept
5 Bond Pull.
2 spares

Pre Burn-In Test Results at -55°C

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 1 TESTING @ -55C

T# 1	.66 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.18 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	4.01 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	3.03 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	4.04 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.54 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-1.1 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	33.3 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-38.3 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-48.5 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-38.2 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-81.5 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.19 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.16 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.19 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.16 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 2 TESTING @ -55C

T# 1	.65 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.19 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	4.40 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.67 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	4.39 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.54 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-.8 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-25.0 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-37.8 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-50.8 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-37.8 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-27.8 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.20 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.16 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.20 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.16 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 3 TESTING @ -55C

T# 1	.64 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.17 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	4.53 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.91 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	4.40 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.04 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-9.5 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-33.1 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-36.8 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-46.4 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-24.2 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-12.4 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.19 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.16 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.19 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.16 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 4 TESTING @ -55C

T# 1	.70 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.23 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	4.37 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	1.94 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.02 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	4.33 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	.6 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-23.4 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-38.4 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-51.5 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-39.7 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-30.1 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.18 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.15 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.18 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.15 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 5 TESTING @ -55C

T# 1	.64 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.17 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	4.32 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	3.01 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	4.28 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.25 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-7.1 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-9.1 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-37.7 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-39.9 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-28.5 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-28.4 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.21 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.16 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.21 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.16 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 6 TESTING @ -55C

T# 1	.69 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.21 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	3.65 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.26 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.07 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	5.52 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-14.7 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-16.3 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-40.5 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-42.3 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-23.4 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-20.8 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.17 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.15 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.17 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.15 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 7 TESTING @ -55C

T# 1	.67 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.19 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	4.24 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.91 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	4.37 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.70 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-.7 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-8.5 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-38.5 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-44.7 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-38.9 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-36.3 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.20 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.15 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.20 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.15 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 8 TESTING @ -55C

T# 1	.67 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.22 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	4.94 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.22 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	4.79 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.36 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-.9 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-6.7 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-39.0 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-46.6 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-39.1 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-38.2 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.20 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.15 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.20 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.15 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 9 TESTING @ -55C

T# 1	.63 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.15 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	4.56 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.88 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	4.53 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	2.97 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-1.2 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-5.3 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-36.3 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-39.0 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-36.8 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-34.3 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.19 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.16 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.19 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.16 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 10 TESTING @ -55C

T# 1	.65 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.19 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	4.34 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	1.45 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	4.47 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	2.29 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-.2 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-2.4 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-37.6 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-40.2 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-37.9 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-37.9 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.17 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.16 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.17 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.16 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 11 TESTING @ -55C

T# 1	.69 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.22 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	4.32 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.82 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	4.93 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	4.79 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-.7 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-.9 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-39.4 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-40.8 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-39.6 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-40.0 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.22 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.17 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.22 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.17 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 12 TESTING @ -55C

T# 1	.63 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.16 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	4.69 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.97 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	4.66 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	2.99 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-1.4 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-3.8 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-37.0 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-38.6 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-35.0 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-34.4 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.22 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.17 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.22 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.17 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

Pre Burn-In Test Results at 25°C

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 1 TESTING @ 25C

T# 1	.56 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.08 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	.57 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	1.00 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	.62 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	1.06 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	.3 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-.9 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-31.9 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-33.5 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-32.2 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-32.5 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	52.5 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	134.9 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.22 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.19 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.57 MA	I SINK	[6 TO 50 MA]
T# 10.2	12.26 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 2 TESTING @ 25C

T# 1	.56 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.07 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	1.22 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	.66 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	1.18 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.82 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	.5 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-1.7 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-31.2 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-33.0 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-31.7 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-31.2 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	54.0 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	138.9 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.23 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.21 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.61 MA	I SINK	[6 TO 50 MA]
T# 10.2	12.17 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 3 TESTING @ 25C

T# 1	.55 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.07 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	.92 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	.68 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	.89 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.76 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	.3 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-1.3 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-31.3 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-33.0 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-31.5 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-31.6 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	54.3 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	140.1 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.23 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.19 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.61 MA	I SINK	[6 TO 50 MA]
T# 10.2	12.33 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 4 TESTING @ 25C

T# 1	.56 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.08 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	1.54 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	-.09 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	1.47 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.11 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	1.2 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-2.1 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-30.6 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-33.3 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-31.7 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-31.0 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	52.9 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	137.5 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.23 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.20 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.45 MA	I SINK	[6 TO 50 MA]
T# 10.2	12.13 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 5 TESTING @ 25C

T# 1	.55 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.06 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	.68 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	.81 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	.74 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.92 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	-.6 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-1.2 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-32.1 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-33.2 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-31.4 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-32.0 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	54.2 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	140.9 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.22 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.19 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.65 MA	I SINK	[6 TO 50 MA]
T# 10.2	12.26 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 6 TESTING @ 25C

T# 1	.56 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.07 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	.87 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	.93 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	.92 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.98 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	.4 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-1.4 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-31.5 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-33.6 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-31.9 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-32.2 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	53.5 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	137.1 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.22 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.20 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.57 MA	I SINK	[6 TO 50 MA]
T# 10.2	12.17 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 7 TESTING @ 25C

T# 1	.56 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.07 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	.87 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	.93 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	.92 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.98 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	.4 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-1.4 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-31.2 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-33.3 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-31.6 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-31.9 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	53.8 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	138.8 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.22 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.19 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.53 MA	I SINK	[6 TO 50 MA]
T# 10.2	12.22 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 8 TESTING @ 25C

T# 1	.55 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.08 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	1.67 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	-.09 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	1.53 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.15 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	1.2 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-2.2 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-30.6 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-33.2 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-31.8 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-30.9 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	56.3 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	145.6 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.23 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.19 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.57 MA	I SINK	[6 TO 50 MA]
T# 10.2	12.29 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 9 TESTING @ 25C

T# 1	.55 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.05 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	.88 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	.89 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	.91 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.95 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	.2 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-1.1 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-31.0 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-32.4 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-31.1 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-31.3 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	53.2 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	138.1 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.29 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.19 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	10.96 MA	I SINK	[6 TO 50 MA]
T# 10.2	12.17 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 10 TESTING @ 25C

T# 1	.56	MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.06	MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	1.44	MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	.28	MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	1.40	MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.40	MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	.6	NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-1.8	NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-30.8	NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-33.1	NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-31.5	NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-31.2	NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	54.7	K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	137.4	K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.24	V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.19	V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.45	MA	I SINK	[6 TO 50 MA]
T# 10.2	12.17	MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 11 TESTING @ 25C

T# 1	.55	MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.07	MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	1.19	MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	.81	MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	1.16	MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.92	MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	.4	NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	.0	NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-31.4	NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-31.8	NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-31.8	NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-31.8	NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	52.8	K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	135.8	K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.24	V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.20	V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.33	MA	I SINK	[6 TO 50 MA]
T# 10.2	12.05	MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 12 TESTING @ 25C

T# 1	.56 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.07 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	1.07 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	.67 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	1.07 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.72 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	.3 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-.1 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-31.6 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-32.0 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-31.8 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-31.8 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	53.2 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	134.9 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.23 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.19 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.49 MA	I SINK	[6 TO 50 MA]
T# 10.2	12.17 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

Pre Burn-In Test Results at +125°C

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 1 TESTING @ 125C

T# 1	.47 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.95 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	5.21 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	3.72 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.11 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.56 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-1.4 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-1.7 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-26.8 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-27.7 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-25.9 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-26.7 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.28 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.23 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.28 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.23 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 2 TESTING @ 125C

T# 1	.47 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.97 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	5.95 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	3.48 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.82 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.40 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-.9 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-2.5 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-26.9 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-28.4 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-26.7 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-26.3 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.26 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.22 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.26 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.22 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 3 TESTING @ 125C

T# 1	.50 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.00 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	5.59 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	3.49 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.40 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.43 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	.1 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-2.5 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-28.5 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-30.1 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-28.6 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-28.1 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.24 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.22 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.24 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.22 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 4 TESTING @ 125C

T# 1	.48 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.97 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	6.12 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.70 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.92 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	2.88 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	2.5 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-2.8 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-26.5 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-28.9 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-28.8 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-26.4 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.29 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.23 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.29 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.23 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 5 TESTING @ 125C

T# 1	.51 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.01 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	5.36 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	3.64 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.26 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.61 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	.9 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-2.2 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-29.3 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-30.4 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-30.6 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-29.0 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.24 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.21 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.24 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.21 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 6 TESTING @ 125C

T# 1	.48 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.97 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	5.56 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	3.23 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.42 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.19 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	1.8 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-1.2 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-27.6 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-28.5 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-29.3 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-27.4 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.27 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.23 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.27 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.23 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 7 TESTING @ 125C

T# 1	.48 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.96 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	5.72 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	3.69 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.60 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.69 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	1.7 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-1.9 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-26.2 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-27.9 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-27.6 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-26.2 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.27 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.23 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.27 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.23 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 8 TESTING @ 125C

T# 1	.46 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.94 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	6.50 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.78 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	6.24 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	2.91 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	2.4 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-2.7 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-25.0 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-26.7 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-27.2 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-24.6 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.28 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.23 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.28 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.23 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 9 TESTING @ 125C

T# 1	.46 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.94 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	5.52 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	.93 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.38 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	.96 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	1.6 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-1.2 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-25.7 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-27.0 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-27.0 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-25.6 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.27 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.23 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.27 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.23 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 10 TESTING @ 125C

T# 1	.47 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.96 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	6.03 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	.19 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.92 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	.29 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	1.4 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-1.9 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-26.6 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-28.5 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-28.0 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-26.5 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.26 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.22 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.26 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.22 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 11 TESTING @ 125C

T# 1	.44 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.92 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	5.63 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	.88 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.47 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	.95 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	1.6 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-.3 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-24.3 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-24.6 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-25.4 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-24.0 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.30 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.26 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.30 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.26 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: PRE BURN-IN ELECTRICAL VERIFICATION SEQ.#: 12

DEVICE 12 TESTING @ 125C

T# 1	.50 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.99 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	5.81 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	3.54 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.65 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.40 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	1.3 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-.9 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-28.0 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-28.9 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-29.0 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-27.4 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.25 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.21 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.25 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.21 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

Post Burn-In Test Results at -55°C

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 1 TESTING @ -55C

T# 1	.69 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.22 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	.52 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	1.03 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	1.78 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	2.29 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	.7 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-.9 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-39.3 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-41.3 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-40.0 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-40.5 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.25 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.16 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.25 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.16 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 2 TESTING @ -55C

T# 1	.65 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.17 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	4.59 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.92 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	4.36 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	2.65 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-1.9 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	6.1 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-38.1 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-76.7 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-37.6 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-73.6 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.18 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.15 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.18 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.15 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 3 TESTING @ -55C

T# 1	.67 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.20 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	4.14 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.53 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	3.44 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.84 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-.1 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-49.8 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-38.7 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-177.6 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-41.9 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-118.3 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.18 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.15 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.18 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.15 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 4 TESTING @ -55C

T# 1	.68 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.21 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	4.49 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	1.95 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	3.94 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	2.43 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	.3 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-5.3 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-38.4 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-88.3 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-39.3 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-73.2 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.17 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.15 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.17 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.15 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 5 TESTING @ -55C

T# 1	.67 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.19 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	3.91 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.80 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	4.19 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.85 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-2.0 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-97.9 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-39.7 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-205.0 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-38.4 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-98.5 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.17 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.16 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.17 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.16 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 6 TESTING @ -55C

T# 1	.69 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.21 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	3.86 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.32 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	4.21 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	4.40 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	.2 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-22.0 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-40.5 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-68.5 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-41.4 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-48.4 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.17 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.15 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.17 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.15 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 7 TESTING @ -55C

T# 1	.67 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.19 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	4.14 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.89 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	3.78 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.05 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-.7 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-76.8 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-38.9 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-158.2 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-39.3 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-71.3 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.19 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.16 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.19 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.16 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 8 TESTING @ -55C

T# 1	.68 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.20 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	4.88 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.27 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	4.20 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	2.34 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	.2 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-11.4 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-38.0 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-58.7 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-39.2 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-45.8 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.18 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.15 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.18 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.15 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 9 TESTING @ -55C

T# 1	.65 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.16 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	4.34 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	3.16 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	4.58 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.68 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-1.0 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	63.5 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-38.2 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-57.9 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-38.2 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-96.5 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.19 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.15 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.19 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.15 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 10 TESTING @ -55C

T# 1	.67 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.20 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	4.95 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.44 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	4.53 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	2.66 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	.0 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	20.4 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-38.1 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-67.2 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-38.9 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-85.4 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.17 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.23 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.17 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.23 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 11 TESTING @ -55C

T# 1	.65 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.16 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	4.50 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.84 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	3.93 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	2.91 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-.9 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	16.6 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-38.2 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-53.5 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-38.4 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-64.2 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.18 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.15 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.18 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.15 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 12 TESTING @ -55C

T# 1	.69 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.20 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	3.90 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.55 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	4.79 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.96 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	.3 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-19.6 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-39.6 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-92.6 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-43.1 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-70.9 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.18 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.15 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.18 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.15 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

Post Burn-In Test Results at 25°C

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 1 TESTING @ 25C

T# 1	.57 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.07 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	.43 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	.88 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	.32 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.80 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	.2 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-.9 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-31.9 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-33.3 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-32.1 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-32.4 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	53.0 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	134.0 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.22 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.19 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.60 MA	I SINK	[6 TO 50 MA]
T# 10.2	12.25 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 2 TESTING @ 25C

T# 1	.55 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.06 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	1.11 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	.62 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	.99 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.59 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	.5 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-1.8 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-31.2 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-32.8 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-31.5 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-31.1 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	54.8 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	136.1 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.22 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.19 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.64 MA	I SINK	[6 TO 50 MA]
T# 10.2	12.29 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 3 TESTING @ 25C

T# 1	.55 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.06 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	.94 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	.56 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	.84 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.59 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	.4 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-1.4 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-31.2 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-33.0 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-31.5 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-31.5 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	55.3 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	140.3 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.22 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.23 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.69 MA	I SINK	[6 TO 50 MA]
T# 10.2	11.93 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 4 TESTING @ 25C

T# 1	.56 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.07 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	1.41 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	-.13 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	1.20 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	-.08 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	1.1 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-2.1 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-30.8 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-33.3 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-31.8 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-31.1 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	53.2 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	133.3 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.22 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.19 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.57 MA	I SINK	[6 TO 50 MA]
T# 10.2	12.26 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 5 TESTING @ 25C

T# 1	.54 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.06 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	.56 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	.68 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	.56 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.70 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	-.7 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-1.3 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-32.0 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-33.2 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-31.2 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-31.8 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	54.5 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	138.9 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.26 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.19 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.37 MA	I SINK	[6 TO 50 MA]
T# 10.2	12.28 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 6 TESTING @ 25C

T# 1	.55 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.06 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	.93 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	.40 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	.81 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.37 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	.9 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-.3 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-32.2 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-33.2 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-33.0 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-32.9 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	50.2 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	129.3 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.23 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.19 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.24 MA	I SINK	[6 TO 50 MA]
T# 10.2	12.01 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 7 TESTING @ 25C

T# 1	.55 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.06 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	.83 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	.74 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	.75 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.67 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	.4 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-1.6 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-31.4 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-33.6 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-31.7 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-31.9 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	53.7 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	138.5 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.22 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.19 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.53 MA	I SINK	[6 TO 50 MA]
T# 10.2	12.20 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 8 TESTING @ 25C

T# 1	.56 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.08 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	1.60 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	-.16 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	1.35 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	-.06 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	1.1 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-2.3 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-31.0 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-33.5 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-32.0 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-31.2 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	56.5 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	143.6 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.22 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.19 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.68 MA	I SINK	[6 TO 50 MA]
T# 10.2	12.36 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 9 TESTING @ 25C

T# 1	.54 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.05 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	.75 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	.77 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	.76 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.77 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	.0 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-1.2 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-31.4 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-32.9 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-31.3 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-31.5 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	53.0 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	134.5 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.22 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.19 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.53 MA	I SINK	[6 TO 50 MA]
T# 10.2	12.21 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 10 TESTING @ 25C

T# 1	.55 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.06 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	1.61 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	.19 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	1.53 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.22 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	.8 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-1.8 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-30.8 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-33.2 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-31.6 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-31.3 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	54.8 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	138.9 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.22 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.25 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.61 MA	I SINK	[6 TO 50 MA]
T# 10.2	11.48 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 11 TESTING @ 25C

T# 1	.55 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.05 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	1.06 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	.63 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	.89 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.61 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	.4 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	-.0 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-31.5 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-32.0 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-31.8 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-31.9 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	52.7 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	133.3 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.22 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.19 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.52 MA	I SINK	[6 TO 50 MA]
T# 10.2	12.17 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 12 TESTING @ 25C

T# 1	.56 MA	+ SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	2.07 MA	+ SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	.95 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 3.2	.51 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.1	.89 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 4.2	.45 MV	V OFFSET 50 OHMS	[-5 TO 5 MV]
T# 5.1	.3 NA	I OFFSET	[-25 TO 25 NA]
T# 5.2	.2 NA	I OFFSET	[-25 TO 25 NA]
T# 6.1	-31.6 NA	+ I BIAS	[-100 TO 100 NA]
T# 6.2	-32.1 NA	+ I BIAS	[-100 TO 100 NA]
T# 7.1	-31.9 NA	- I BIAS	[-100 TO 100 NA]
T# 7.2	-31.9 NA	- I BIAS	[-100 TO 100 NA]
T# 8.1	53.4 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 8.2	134.4 K	OPEN LOOP GAIN	[50 TO 1E12 K]
T# 9.1	.22 V	V OUT LOW	[0 TO 0.4 V]
T# 9.2	.19 V	V OUT LOW	[0 TO 0.4 V]
T# 10.1	11.49 MA	I SINK	[6 TO 50 MA]
T# 10.2	12.20 MA	I SINK	[6 TO 50 MA]

PASS BIN 1

Post Burn-In Test Results at +125°C

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 1 TESTING @ 125C

T# 1	.39 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.85 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	4.84 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	3.36 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	4.60 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.04 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-1.1 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-1.9 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-22.1 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-22.9 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-21.3 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-21.6 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.35 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.28 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.35 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.28 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 2 TESTING @ 125C

T# 1	.40 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.87 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	5.53 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	3.14 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.27 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	2.91 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-.7 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-2.4 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-22.2 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-23.1 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-21.7 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-21.3 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.33 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.28 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.33 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.28 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 3 TESTING @ 125C

T# 1	.42 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.89 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	5.51 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	3.14 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.29 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	2.97 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	-.8 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-1.9 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-22.8 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-23.7 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-22.1 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-22.1 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.32 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.27 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.32 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.27 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 4 TESTING @ 125C

T# 1	.40 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.91 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	6.02 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.51 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.57 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	2.20 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	.4 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-2.0 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-21.6 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-23.6 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-22.1 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-20.9 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.38 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.30 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.38 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.30 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 5 TESTING @ 125C

T# 1	.38 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.84 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	5.06 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	3.29 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	4.85 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.17 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	.6 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-1.7 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-21.5 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-22.6 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-22.2 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-20.0 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.37 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.30 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.37 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.30 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 6 TESTING @ 125C

T# 1	.40 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.86 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	5.11 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	3.02 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	4.85 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	2.70 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	1.8 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-.9 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-22.7 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-23.1 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-24.1 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-22.2 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.37 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.30 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.37 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.30 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 7 TESTING @ 125C

T# 1	.39 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.85 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	5.34 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	3.39 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.08 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.02 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	1.4 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-1.7 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-21.3 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-22.5 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-22.7 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-20.9 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.37 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.30 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.37 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.30 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 8 TESTING @ 125C

T# 1	.40 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.87 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	6.22 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.28 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.86 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	2.17 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	1.5 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-1.9 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-22.0 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-23.2 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-23.2 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-20.9 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.35 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.28 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.35 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.28 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 9 TESTING @ 125C

T# 1	.38 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.84 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	5.23 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	3.39 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.04 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	3.16 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	1.0 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-1.4 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-21.1 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-21.8 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-22.0 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-20.4 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.37 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.30 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.37 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.30 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 10 TESTING @ 125C

T# 1	.37 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.84 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	6.15 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	2.72 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.87 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	2.59 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	1.8 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-1.8 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-20.9 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-21.9 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-22.1 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-20.3 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.39 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.30 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.39 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.30 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 11 TESTING @ 125C

T# 1	.37 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.84 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	5.50 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	3.18 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.13 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	2.92 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	1.1 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-.8 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-20.9 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-21.4 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-22.0 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-20.8 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.39 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.32 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.39 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.32 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

JOB NUMBER: DDS-101-17-A TEST POINT: POST BURN-IN ELECTRICAL VERIFICATION SEQ.#: 14

DEVICE 12 TESTING @ 125C

T# 1	.38 MA	+	SUPPLY CURRENT	[0.1 TO 1 MA]
T# 2	1.84 MA	+	SUPPLY CURRENT	[0.1 TO 2.5 MA]
T# 3.1	5.42 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 3.2	3.09 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.1	5.17 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 4.2	2.86 MV	V	OFFSET 50 OHMS	[-9 TO 9 MV]
T# 5.1	1.2 NA	I	OFFSET	[-100 TO 100 NA]
T# 5.2	-.9 NA	I	OFFSET	[-100 TO 100 NA]
T# 6.1	-21.4 NA	+	I BIAS	[-300 TO 300 NA]
T# 6.2	-21.0 NA	+	I BIAS	[-300 TO 300 NA]
T# 7.1	-22.3 NA	-	I BIAS	[-300 TO 300 NA]
T# 7.2	-20.7 NA	-	I BIAS	[-300 TO 300 NA]
T# 8.1	.37 V	V	OUT LOW	[0 TO 0.7 V]
T# 8.2	.30 V	V	OUT LOW	[0 TO 0.7 V]
T# 9	.37 V	V	OUT LOW	[0 TO 0.4 V]
T# 9.1	.30 V	V	OUT LOW	[0 TO 0.4 V]

PASS BIN 1

Scanning Electron Microscopy (SEM) analysis

TANDEX TEST LABS, INC.

15849 Business Ctr. Dr. Irwindale CA. 91706
Phone: (626)-962-7166 Fax: (626)-960-6896

SCANNING ELECTRON MICROSCOPE ANALYSIS

DIE DEVICES
TTL Job # DDS-101-17-W
Date: July 09, 2018
Part Number: LM193
Part Type: VOLTAGE COMPARATOR MICROCIRCUIT
Lot: Lot# 430549 D/C: 1810 WFR# 30
Quantity: Eight (8)
Purchase Order: SS139

Submitted by: _____
Jason A. Salinas
DPA/MTS

Approved by: Deborah M. Gorham
Deborah M. Gorham
Quality Assurance

TANDEX TEST LABS TTL Job # DDS-101-17-W

Summary

Eight (8) Voltage Comparator Microcircuit P/N: LM193 were submitted by Die Devices for Scanning Electron Microscopy Analysis. This Analysis was performed in accordance with Mil-Std-883, Method 2018.6 The devices were assigned sample number 1 through 8 by Tandex Test Labs.

1. **Plasma Etching** Carbon Tetraflouride Gas 92% and 8% Oxygen was used to remove the glassivation. This etching is destructive and uneven in the rates of glass removal in various areas of the die.

2. **SEM Inspection** was performed on all eight devices. All eight devices revealed adequate metallization coverage and met the requirements of MIL-STD-883, Method 2018.6. See DPA form on page 3 and figures 1 through 3, for typical photographs.

Conclusion: This lot is acceptable for use.

TANDEX TEST LABS TTL Job # DDS-101-17-W
SEM EXAMINATION

TTL Job No.	Part Number	Part Type	Date
DDS-101-17-W	LM193	Voltage Comparator Microcircuit	June 27, 2018
Lot Date Code: WFR# 30 Lot# 430549 D/C: 1810	Sample Qty. 8	Serial Numbers 1 - 8	Test Specifications Mil-Std-883 Method 2018.6
Misc. ID No.	Qty . Accept 8	Qty. Reject 0	Qty. Suspect 0

Notes:

S/N	Investigation Findings / Comments	A/R/S
1	No Anomalies	A
2	No Anomalies	A
3	No Anomalies	A
4	No Anomalies	A
5	No Anomalies	A
6	No Anomalies	A
7	No Anomalies	A
8	No Anomalies	A

Each sample was inspected for the general metallization condition at a magnification between 1,000 X and 6,000 X over 25% of the total metallization (unless specified differently). Each sample was inspected from four (4) viewing directions at a magnification between 5,000 X and 20,000 X

Inspection required Yes: X No: Devices constructed with expanded Metallization Yes: X No:

Sample Glassivated Yes: X No: Dual Level Metallization Yes: No: X

Glassivation Removed Using: PLASMA ETCHING

Beam accelerating voltage **10kV to 20kV** Viewing angle **45 deg**

TTL 4

Technician Stamp:

TANDEX TEST LABS TTL Job # DDS-101-17-W

Photodocumentation

TANDEX TEST LABS TTL Job # DDS-101-17-W

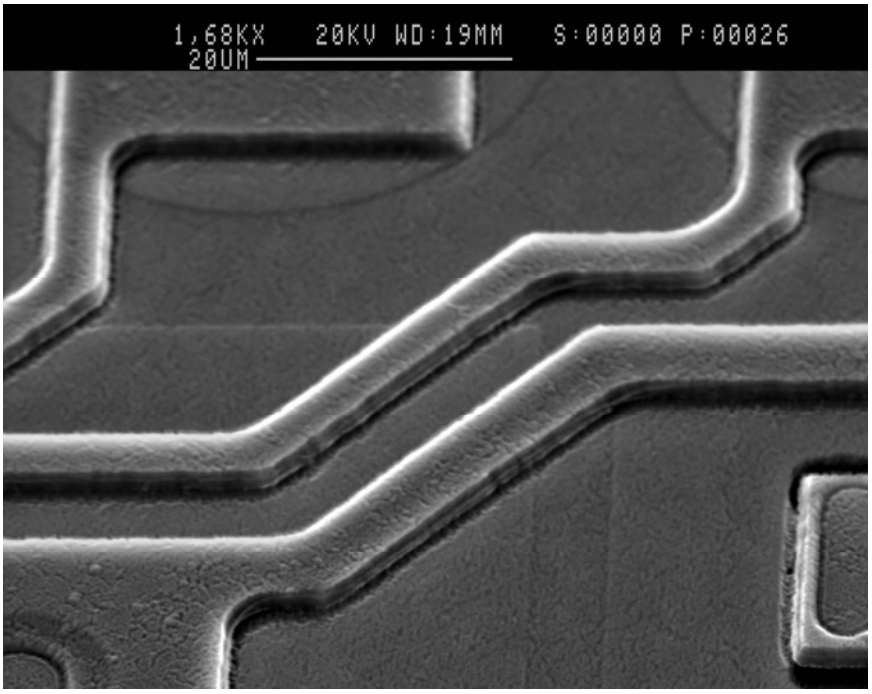

Fig: 1

Mag: 1,680X

S/N: 4

Description: SEM photograph of general metallization.

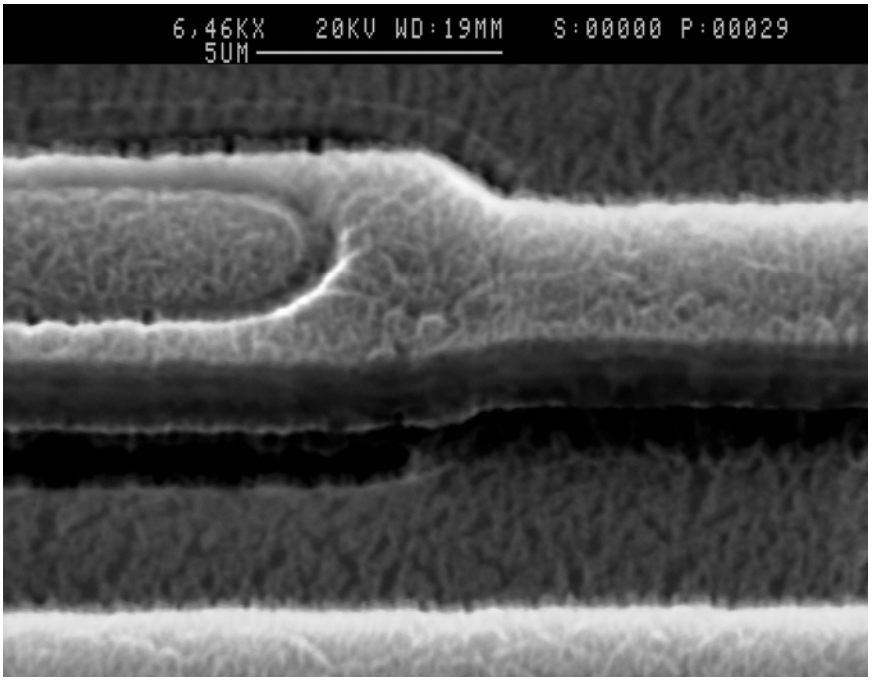

Fig: 2

Mag: 6,460X

S/N: 4

Description: SEM photograph of metallization typical step.

TANDEX TEST LABS TTL Job # DDS-101-17-W

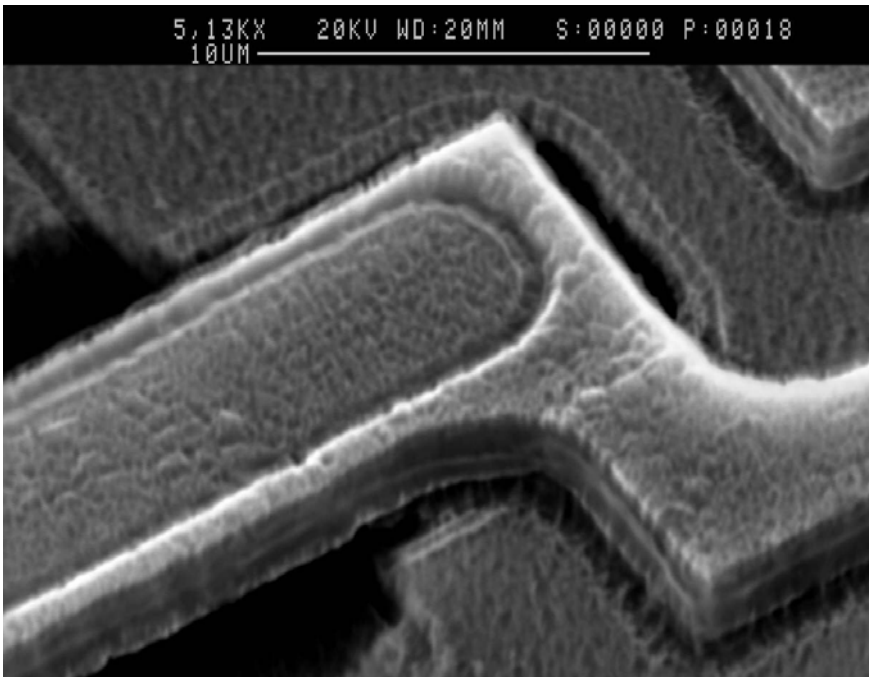

Fig: 3

Mag: 5,130X

S/N: 4

Description: SEM photograph of typical contact window device.

TANDEX TEST LABS, INC.

15849 Business Center. Dr., Irwindale CA. 91706
Phone: (626)962-7166 FAX: (626)960-6896
http://www.tandexlabs.com
e-mail: via web site

Certificate of Conformance

CUSTOMER:	Silicon Supplies Limited 47 Wherry Road Norwich, NR1, 1WS United Kingdom Vat GB# 114 3513 56	DATE:	July 09, 2018
TEST REPORT:	DDS-101-17-W	QUANTITY REQUIRED:	8
P.O. NUMBER:	SS139	QUANTITY PROCESSED:	8
DESCRIPTION:	VOLTAGE COMPARATOR MICROCIRCUIT	QUANTITY PASSED:	8
PART NUMBER(S):	LM193	QUANTITY FAILED:	0
MFG PART NUMBER	LM193	QUANTITY SHIPPING:	8
LOT / DATE CODE:	LOT# 430549 WFR# 30 D/C: 1810		
MFG:	SILICON SUPPLIES		

METHOD OF TESTING: MIL-STD-883 METHOD 2018.6

I hereby certify that the subject components have been processed and inspected in accordance with instructions with specifications referenced in your purchase order. Physical records and/or data pertinent to applicable military, proprietary, and/or commercial specifications are on file and available upon request for inspection at this facility.

Deborah M. Gorham

QA TANDEX 2

Deborah M. Gorham
QUALITY ASSURANCE